

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS:

WEBER, M.A. 1 PCT

PCT NO.:

PCT/DE2003/003781

FILED:

**NOVEMBER 14, 2003** 

TITLE:

DEVICE AND METHOD FOR MEASURING SURFACES ON THE

INTERNAL WALLS OF CYLINDERS USING CONFOCAL MICRO-

**SCOPES** 

## INFORMATION DISCLOSURE STATEMENT

MAIL STOP PCT

Commissioner of Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Applicant is enclosing Form PTO-1449 disclosing the references cited in the International Search Report, copy enclosed. As it is believed that copies of the references cited in the Search Report were forwarded by the International Office, we are not enclosing copies of these references. Since the instant Information Disclosure Statement is being filed concurrently with the application, no official fee is required in connection with the same. It is respectfully requested that the foregoing Information Disclosure Statement be incorporated into the official file of the concurrently-filed PCT patent application.

Respectfully submitted,

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Enclosures: PTO-1449 form and International Search Report

EXPRESS MAIL NO.

EL 723897846 US

Date of Deposit May 10, 2005

I hereby certify that this paper or fee is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 C.F.R. § 1.10, on the date indicated above, and is addressed to the

Commissioner of Patents, P.O. Box 1450, Alexandria, VA

Melissa Konko

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				U.S.	P/	ATENT DOCUMENTS					
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	AA	4,05	5,382	10/1977		Ziekman, et al.					
	AB	4,96	3,018	10/1990		West					
	AC	5 64	0 270	6/1997		Aziz et al.					
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	AR		"Endoscope-compatible confocal microscope using a gradient index-lens system", Knittel J. et al., Optics Communications, North-Holland Publishing Co. Amsterdam, NL, vol. 188, no. 5-6, pages 267-273, February 15, 2001.								
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EXAMINER DATE CONSIDERED

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'EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.